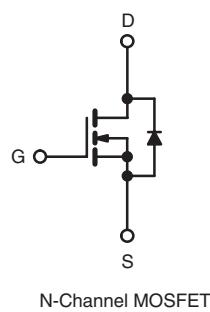
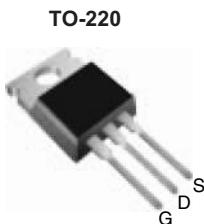


Power MOSFET

PRODUCT SUMMARY	
V_{DS} (V)	400
$R_{DS(on)}$ (Ω)	$V_{GS} = 10$ V 0.55
Q_g (Max.) (nC)	63
Q_{gs} (nC)	9.0
Q_{gd} (nC)	32
Configuration	Single



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- Ease of Parallelizing
- Simple Drive Requirements
- Lead (Pb)-free Available



RoHS*
COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION

Package	TO-220
Lead (Pb)-free	IRF740PbF SiHF740-E3
SnPb	IRF740 SiHF740

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V_{DS}	400	V
Gate-Source Voltage		V_{GS}	± 20	
Continuous Drain Current	V_{GS} at 10 V	I_D	10	A
	$T_C = 25$ °C		6.3	
Pulsed Drain Current ^a		I_{DM}	40	W/°C
Linear Derating Factor			1.0	
Single Pulse Avalanche Energy ^b		E_{AS}	520	mJ
Repetitive Avalanche Current ^a		I_{AR}	10	A
Repetitive Avalanche Energy ^a		E_{AR}	13	mJ
Maximum Power Dissipation	$T_C = 25$ °C	P_D	125	W
Peak Diode Recovery dV/dt ^c		dV/dt	4.0	V/ns
Operating Junction and Storage Temperature Range		T_J, T_{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	
Mounting Torque	6-32 or M3 screw		10	lbf · in
			1.1	N · m

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = 50$ V, starting $T_J = 25$ °C, $L = 9.1$ mH, $R_G = 25 \Omega$, $I_{AS} = 10$ A (see fig. 12).
- $I_{SD} \leq 10$ A, $dI/dt \leq 120$ A/ μ s, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.
- 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	1.0	

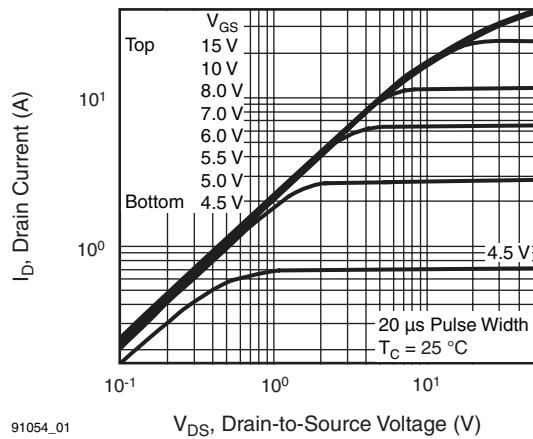
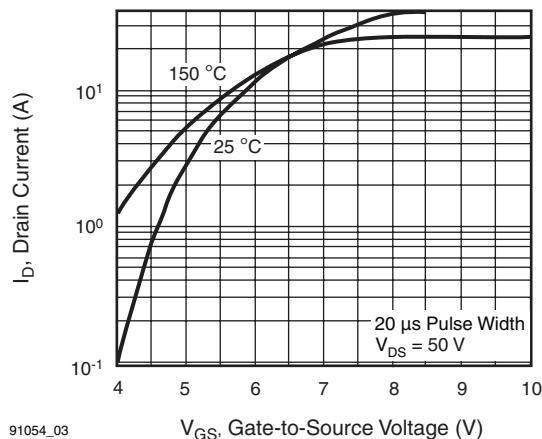
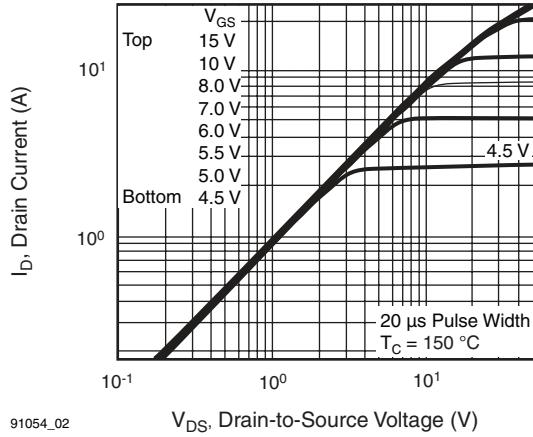
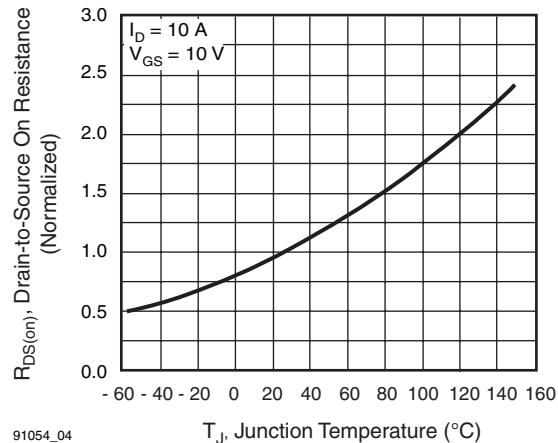
SPECIFICATIONS $T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	400	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}$	-	0.49	-	$\text{V}/^{\circ}\text{C}$
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.0	-	4.0	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	25	μA
		$V_{DS} = 320 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125 \text{ }^{\circ}\text{C}$	-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 6.0 \text{ A}^b$	-	-	Ω
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}, I_D = 6.0 \text{ A}^b$		5.8	-	S
Dynamic						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz, see fig. 5}$	-	1400	-	pF
Output Capacitance	C_{oss}		-	330	-	
Reverse Transfer Capacitance	C_{rss}		-	120	-	
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 10 \text{ A}, V_{DS} = 320 \text{ V},$ see fig. 6 and 13 ^b	-	-	63
Gate-Source Charge	Q_{gs}			-	-	9.0
Gate-Drain Charge	Q_{gd}			-	-	32
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 200 \text{ V}, I_D = 10 \text{ A}$	$R_G = 9.1 \Omega, R_D = 20 \Omega, \text{ see fig. 10}^b$	-	14	-
Rise Time	t_r			-	27	-
Turn-Off Delay Time	$t_{d(off)}$			-	50	-
Fall Time	t_f			-	24	-
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-
Internal Source Inductance	L_S			-	7.5	-
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	10
Pulsed Diode Forward Current ^a	I_{SM}			-	-	40
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}, I_S = 10 \text{ A}, V_{GS} = 0 \text{ V}^b$	-	-	2.0	V
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}, I_F = 10 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	370	790
Body Diode Reverse Recovery Charge	Q_{rr}			-	3.8	8.2
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2 \%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics, $T_C = 25 \text{ }^\circ\text{C}$

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics, $T_C = 150 \text{ }^\circ\text{C}$

Fig. 4 - Normalized On-Resistance vs. Temperature

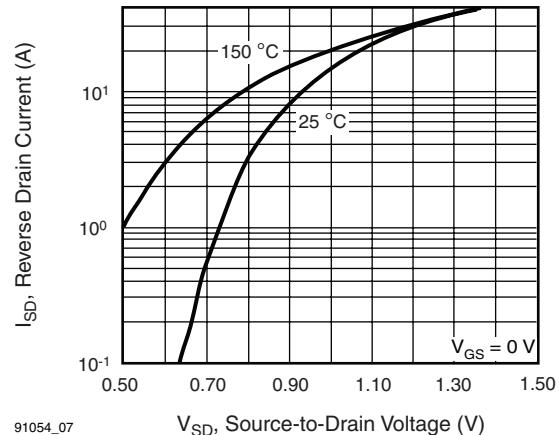
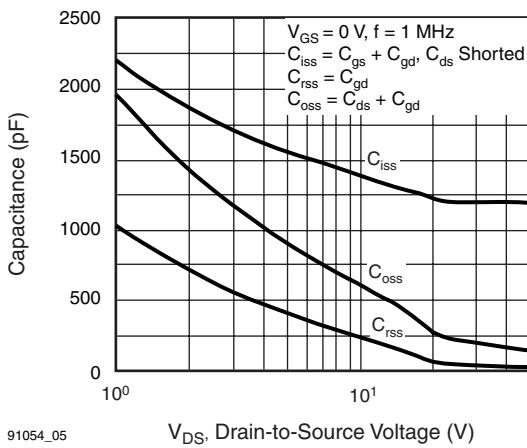


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

Fig. 7 - Typical Source-Drain Diode Forward Voltage

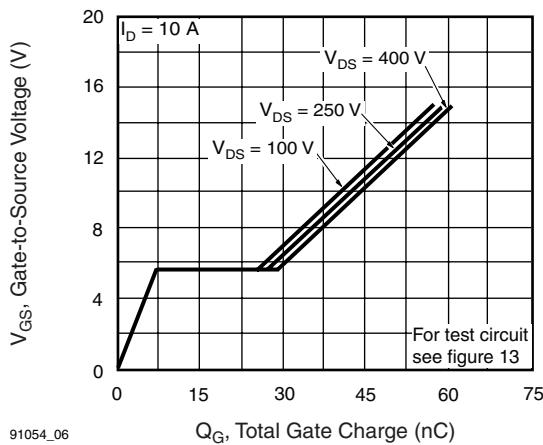


Fig. 6 - Typical Gate Charge vs. Drain-to-Source Voltage

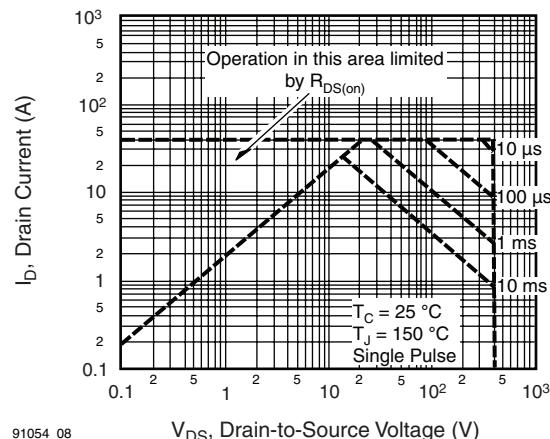
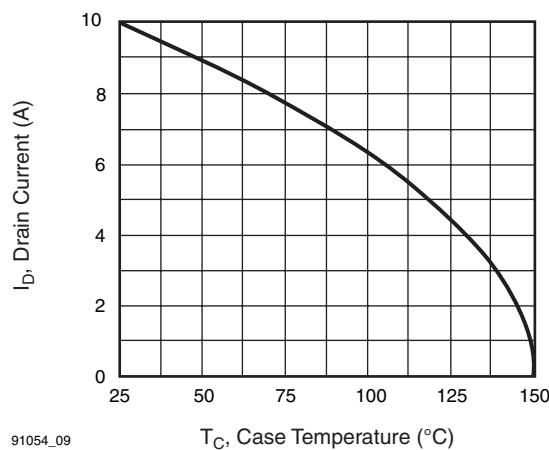
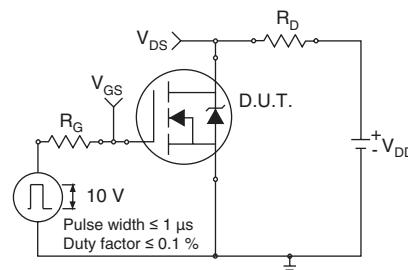
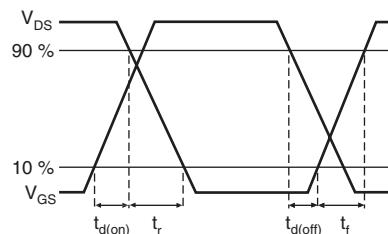
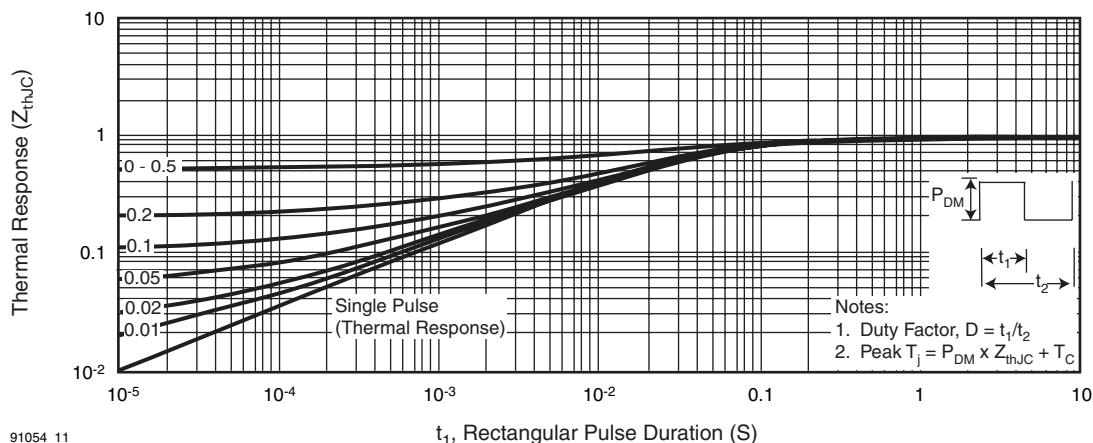
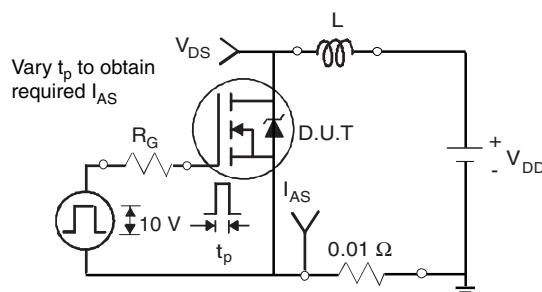
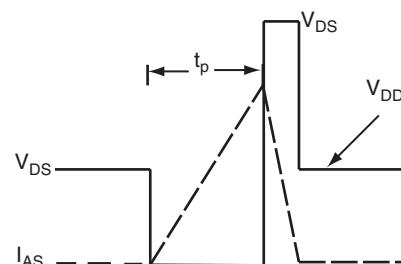


Fig. 8 - Maximum Safe Operating Area


Fig. 9 - Maximum Drain Current vs. Case Temperature

Fig. 10a - Switching Time Test Circuit

Fig. 10b - Switching Time Waveforms

Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

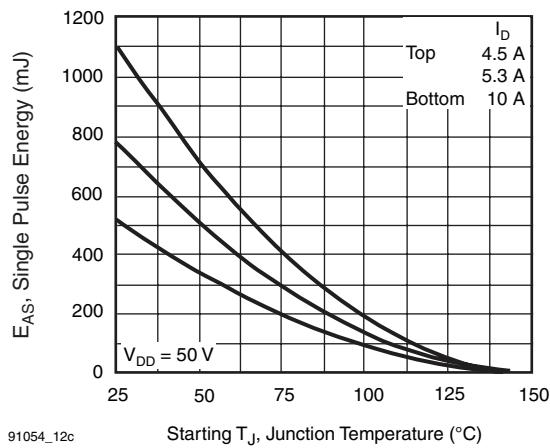


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

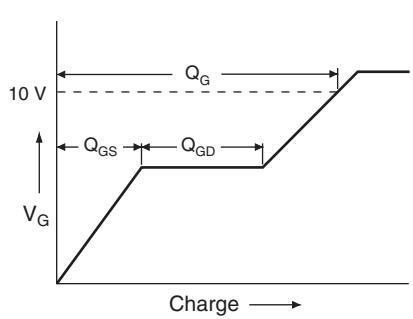


Fig. 13a - Basic Gate Charge Waveform

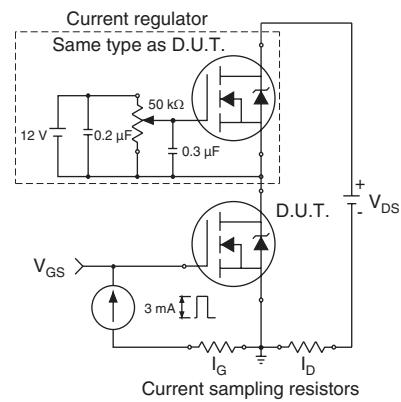
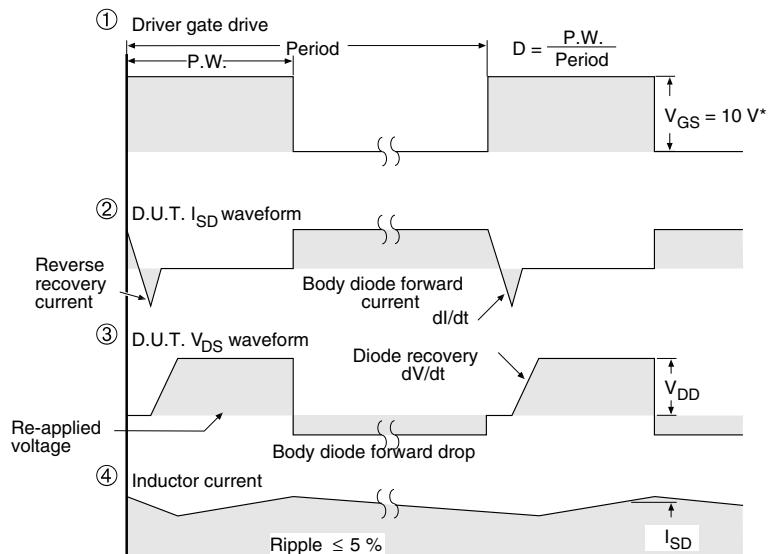
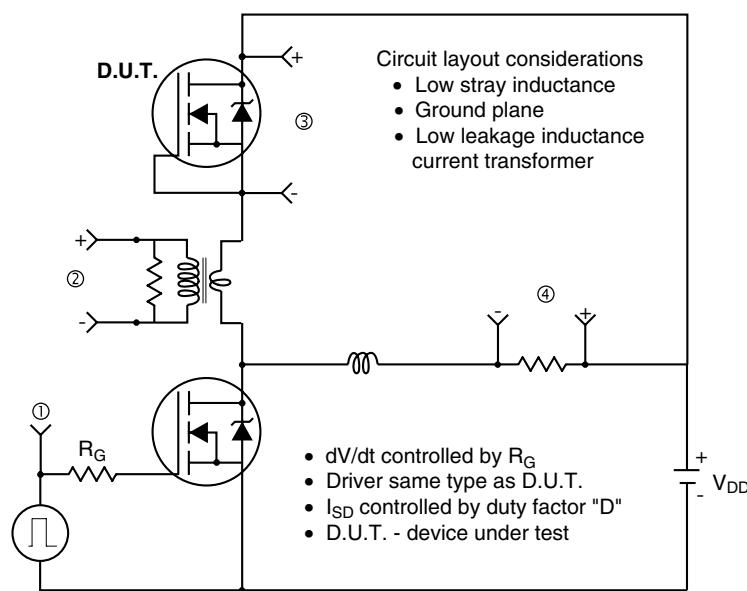


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel

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